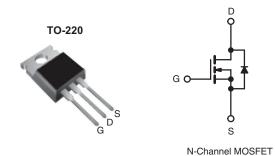


Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	250				
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.28			
Q _g (Max.) (nC)	68				
Q _{gs} (nC)	11				
Q _{gd} (nC)	35				
Configuration	Single				



FEATURES

- Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available



DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRF644PbF
Lead (FD)-liee	SiHF644-E3
SnPb	IRF644
SIFU	SiHF644

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	250	.,	
Gate-Source Voltage			V_{GS}	± 20	V	
Continuous Drain Current	V _{GS} at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$		14	А	
		T _C = 100 °C	I _D	8.5		
Pulsed Drain Current ^a			I _{DM}	56		
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	550	mJ	
Repetitive Avalanche Currenta			I _{AR}	14	Α	
Repetitive Avalanche Energy ^a			E _{AR}	13	mJ	
Maximum Power Dissipation	T _C = 25 °C		P_{D}	125	W	
Peak Diode Recovery dV/dtc			dV/dt	4.8	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d]	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
				1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 4.5 \,\text{mH}$, $R_G = 25 \,\Omega$, $I_{AS} = 14 \,\text{A}$ (see fig. 12).
- c. $I_{SD} \le 14$ A, $dI/dt \le 150$ A/ μ s, $V_{DD} \le V_{DS}$, $T_{J} \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0		

PARAMETER	SYMBOL	vise noted TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static	· · · · · · · · · · · · · · · · · · ·	. = 0				1	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		250	-	-	V
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	Reference to 25 °C, $I_D = 1$ mA		-	0.34	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20 \text{ V}$		-	± 100	nA
		V _{DS} = 250 V, V _{GS} = 0 V		-	-	25	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 200 V	V _{DS} = 200 V, V _{GS} = 0 V, T _J = 125 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 8.4 A ^b	-	-	0.28	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	50 V, I _D = 8.4 A ^b	6.7	-	-	S
Dynamic							,
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$		-	1300	-	pF
Output Capacitance	C _{oss}			-	330	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.	f = 1.0 MHz, see fig. 5		85	-	
Total Gate Charge	Qg		$V_{GS} = 10 \text{ V}$ $I_D = 7.9 \text{ A}, V_{DS} = 200 \text{ V},$ see fig. 6 and 13 ^b	=	-	68	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	11	
Gate-Drain Charge	Q _{gd}			-	-	35	
Turn-On Delay Time	t _{d(on)}	$V_{DD}=125~V,~I_D=7.9~A,$ $R_G=9.1~\Omega,~R_D=8.7~\Omega,~see~fig.~10^b$		-	11	-	- ns
Rise Time	t _r			-	24	-	
Turn-Off Delay Time	t _{d(off)}			-	53	-	
Fall Time	t _f			-	49	-	
Internal Drain Inductance	L_{D}	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						,
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	14	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	56	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 14 A, V _{GS} = 0 V ^b		ı	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 ^{\circ}\text{C}, \ I_F = 7.9 \text{A}, \ \text{dI/dt} = 100 \text{A/}\mu\text{s}^b$		-	250	500	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	2.3	4.6	μС
Forward Turn-On Time	t _{on}	Intrinsic tu	on is don	ninated b	v L _S and I	L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

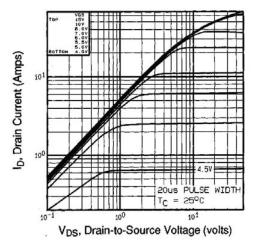


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

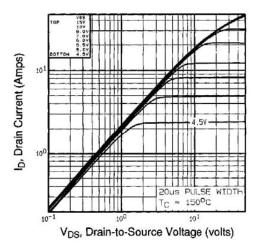


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

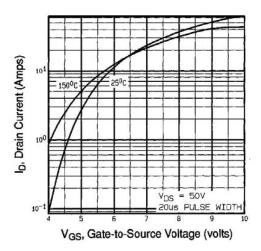


Fig. 3 - Typical Transfer Characteristics

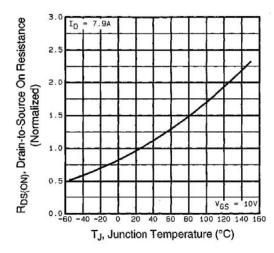


Fig. 4 - Normalized On-Resistance vs. Temperature



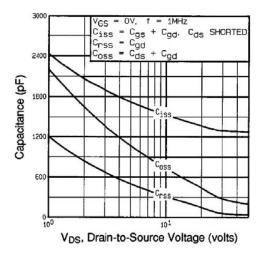


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

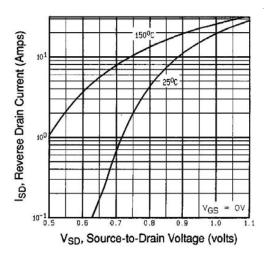


Fig. 7 - Typical Source-Drain Diode Forward Voltage

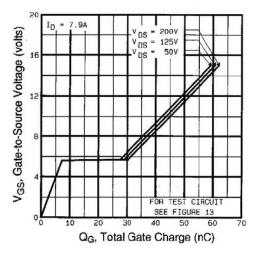


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

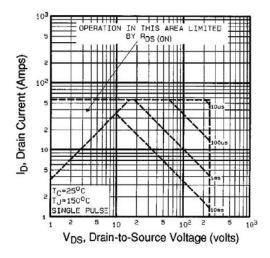


Fig. 8 - Maximum Safe Operating Area





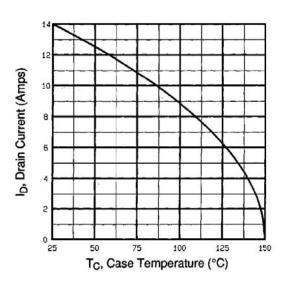


Fig. 9 - Maximum Drain Current vs. Case Temperature

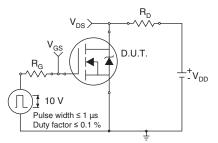


Fig. 10a - Switching Time Test Circuit

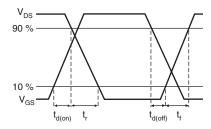


Fig. 10b - Switching Time Waveforms

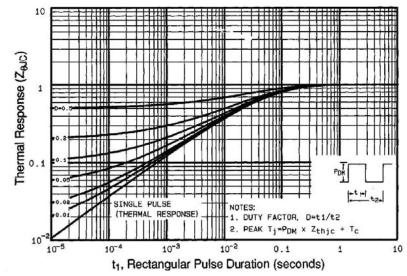


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

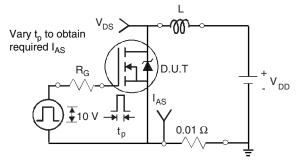


Fig. 12a - Unclamped Inductive Test Circuit

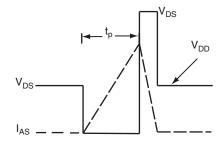


Fig. 12b - Unclamped Inductive Waveforms



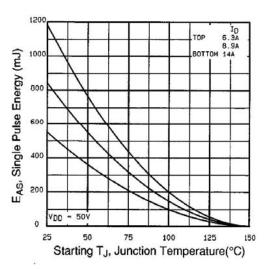


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

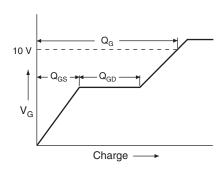


Fig. 13a - Basic Gate Charge Waveform

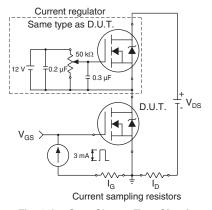
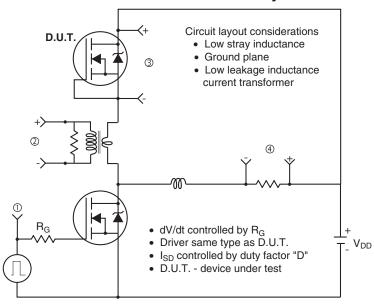
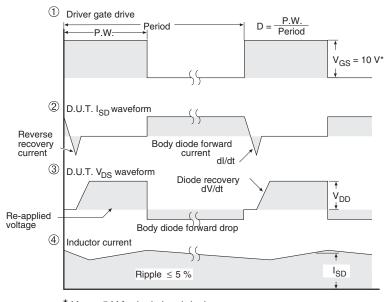


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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